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Frozen lattice and absorptive model for high angle annular dark field scanning transmission electron microscopy: a comparison study in terms of integrated intensity and atomic column position measurement

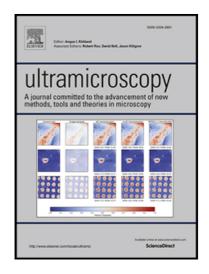
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Highlights

- STEM images are simulated using the frozen phonon and absorptive potential model.
- Both models are compared in a quantitative manner.
- A comparison is made in terms of integrated intensity and precision.
- For high angles and large thicknesses, the AP model underestimates the integrated intensity.
- Comparable results are predicted for the precision with which atomic columns can be located.

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